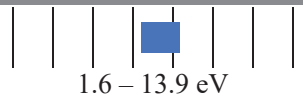
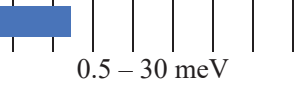
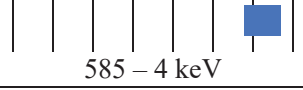

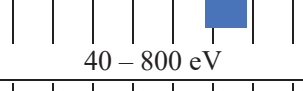
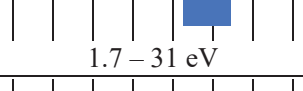
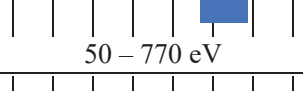
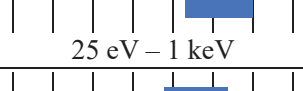
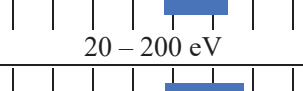


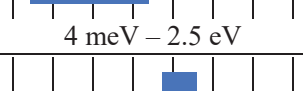
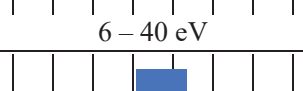
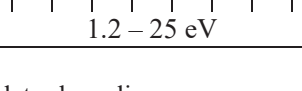


Beamlines at UVSOR

II

Beamline	Monochromator / Spectrometer	Energy Range	Targets	Techniques	Contact
BL1U	Free electron laser	 1.6 – 13.9 eV		(Irradiation)	Y. Taira yostaira@ims.ac.jp
BL1B	Martin-Puplett FT-FIR	 0.5 – 30 meV	Solid	Reflection Absorption	K. Tanaka k-tanaka@ims.ac.jp
BL2A	Double crystal	 585 – 4 keV	Solid	Reflection Absorption	F. Matsui matui@ims.ac.jp
BL2B	18-m spherical grating (Dragon)	 23 – 205 eV	Solid	Photoemission	S. Kera kera@ims.ac.jp
BL3U	Varied-line-spacing plane grating (Monk-Gillieson)	 40 – 800 eV	Gas Liquid Solid	Absorption Photoemission Photon-emission	H. Iwayama iwayama@ims.ac.jp
BL3B	2.5-m off-plane Eagle	 1.7 – 31 eV	Solid	Reflection Absorption Photon-emission	F. Matsui matui@ims.ac.jp
BL4U	Varied-line-spacing plane grating (Monk-Gillieson)	 50 – 770 eV	Gas Liquid Solid	Absorption (Microscopy)	T. Ohigashi ohigashi@ims.ac.jp
BL4B	Varied-line-spacing plane grating (Monk-Gillieson)	 25 eV – 1 keV	Gas Solid	Photoionization Photodissociation Photoemission	H. Iwayama iwayama@ims.ac.jp
BL5U	Spherical grating (SGM-TRAIN [†])	 20 – 200 eV	Solid	Photoemission	K. Tanaka k-tanaka@ims.ac.jp
BL5B	Plane grating	 6 – 600 eV	Solid	Calibration Absorption	K. Tanaka k-tanaka@ims.ac.jp
BL6U*	Variable-included-angle varied-line-spacing plane grating	 45 – 600 eV	Gas Solid	Photoionization Photodissociation Photoemission	F. Matsui matui@ims.ac.jp
BL6B	Michelson FT-IR	 4 meV – 2.5 eV	Solid	Reflection Absorption IR microscope	K. Tanaka k-tanaka@ims.ac.jp
BL7U	10-m normal incidence (modified Wadsworth)	 6 – 40 eV	Solid	Photoemission	K. Tanaka k-tanaka@ims.ac.jp
BL7B	3-m normal incidence	 1.2 – 25 eV	Solid	Reflection Absorption Photon-emission	F. Matsui matui@ims.ac.jp

Yellow columns represent undulator beamlines.

* In-house beamline.